

AMENDMENTS TO THE SPECIFICATION

Please amend the paragraph beginning at page 1, line 26, as follows:

Internally, a JTAG-compliant device contains a test access protocol (TAP) controller, a state machine whose state is controlled by the signal received on the control (TMS) line. By traversing the different states of the test access protocol (TAP) controller, data can be loaded into and read from internal data and instruction registers, typically for the purpose of determining the proper operation of the device. For example, an instruction can be loaded, followed by data which is processed according to the loaded instruction. For more details on the JTAG-IEEE 1149.1 specification, please refer to IEEE's website: <http://www.ieee.org>.

Please amend the paragraph beginning at page 5, line 11, as follows:

Figure 2 is ~~[[a]]~~ an overview of a logic state diagram illustrating the operation of the test access protocol (TAP) controller of a JTAG-compliant device;

Please amend the paragraph beginning at page 8, line 17, as follows:

Figure 2 is ~~[[a]]~~ an overview of a logic state diagram illustrating the operation of the test access protocol (TAP) controller of a JTAG-compliant device. During initialization, the test access protocol (TAP) controller is placed at the Test-Logic-Reset state. The test access protocol (TAP) controller is configured to return to the Test-Logic-Reset state upon the test access protocol (TAP) controller's receiving of a reset signal (through the common reset (TRST) line). The changing of the state of the test access protocol (TAP) controller is controlled by the signal received through the control (TMS) line. The "0" and "1" arrows show how the state of the test access protocol (TAP) controller changes depending on whether the test access protocol (TAP) controller receives a low or high signal through the control line. The flowchart of Figure 3 provides more details on the

behavior of the TAP controller at the states: test-logic-reset 200, run-test/idle state 205, select-data-register-scan state 210, select-instruction-register-scan 250, update-data-register state 240, and update-instruction-register 280.